

Run-to-Run Control: Application to Oxidation Processes

Kostas Tsakalis, ASU (on sabbatical leave with SEMY Eng. Inc.)

Mark Yelverton, Brian Cusson, AMD

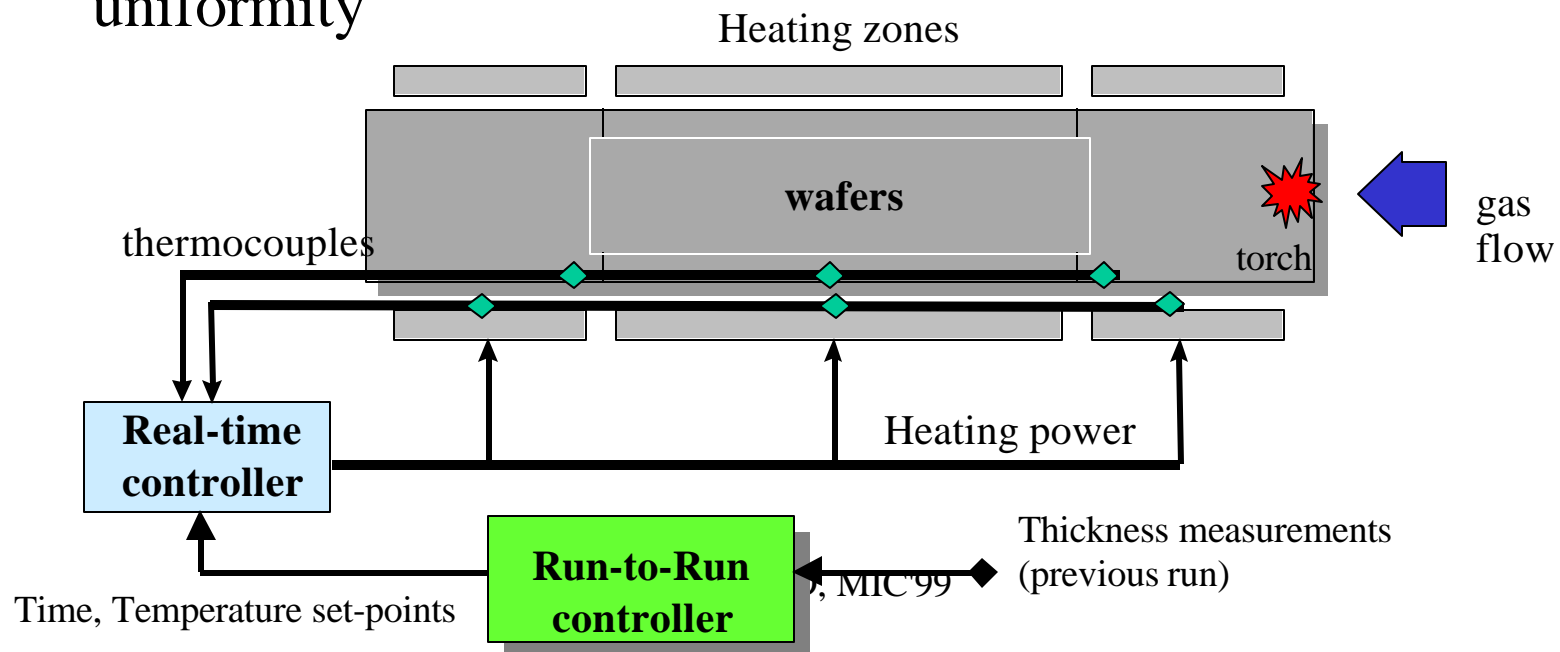
Kevin Stoddard, Brad Schulze, SEMY Eng. Inc.

Introduction

- Run-to-Run Control Problem in Diffusion Furnaces
- ARRC Algorithms
 - Control input updates
 - Parameter estimation
- Application to a wet-oxidation test process
- Conclusions

Run-to-Run Control in Diffusion

- Wet oxidation process for silicon oxidation
- Loss of symmetry due to thermal gradients, possible long-term drift
- R2R control inputs: processing time, temperature set-points
- Objectives: minimize deviations from target, across-the-load uniformity



ARRC Algorithms

- SEMY's ARRC (Advanced Run-to-Run Control)
 - Automatic data collection and recipe adjustment
- Modeling: Least squares fit of experimental data

$$\mathbf{q} = \arg \min_{\mathbf{q}} \{ \| y_k - f[u_k, \mathbf{q}] \| \}$$

- u_k = inputs/manipulated variables, y_k = measured outputs
- Issues: Parameterization, Excitation
- Fitting error: Determines control/adaptation dead-zones

ARRC Algorithms (control)

- Control Updates: Newton-like corrections

$$u_{k+1} = u_k + \mathbf{g}_c w_{c,k} e_{c,k} / (1 + \mathbf{g}_c w_{c,k} ' w_{c,k}), \quad w_{c,k} = \partial f / \partial u$$

- Standard trade-off between speed of convergence/drift attenuation and steady-state variance
- Nonlinear gain: $\mathbf{g}_c = \mathbf{g} (e_{c,k} / \mathbf{g}_{dz})^2 / [1 + (e_{c,k} / \mathbf{g}_{dz})^2]$
 - Quick correction of large errors, to maintain fast convergence
 - Slow correction of small errors, to keep the steady-state variance small.

ARRC Algorithms (model adaptation)

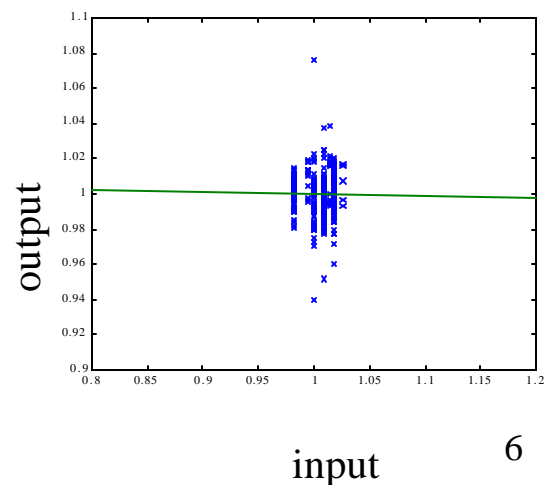
- Parameter Updates: Fading-memory least-squares

$$\mathbf{q}_{k+1} = \Pi\{\mathbf{q}_k + \mathbf{g}_p P_k^{-1} w_{p,k} e_{p,k} / (1 + \mathbf{g}_p w_{p,k} P_k^{-1} w_{p,k})\}$$

$$P_{k+1} = \mathbf{a}P_k + (1 - \mathbf{a})Q + \mathbf{g}_p \mathbf{a}w_{p,k} w_{p,k}'$$

- $w_p = \partial f / \partial \mathbf{q}$, $a =$ fading memory
- Π : parameter projection on a constraint set
- Parameter projections and dead-zones are important to provide some immunity to noise-induced parameter drift
- Ability to perform partial adaptation

- Note: Adaptation constraints are essential since segments of production data may (and do) happen to fit to an opposite slope (insufficient excitation). In such a case, the adaptation may drift to a burst and cause product scrap.

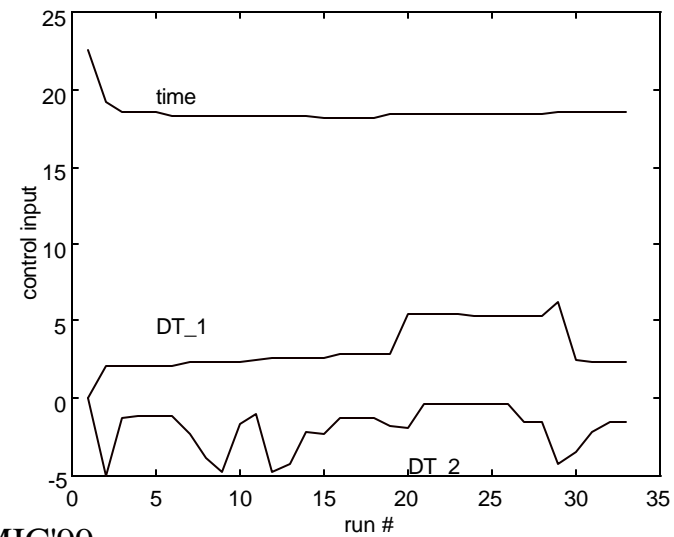
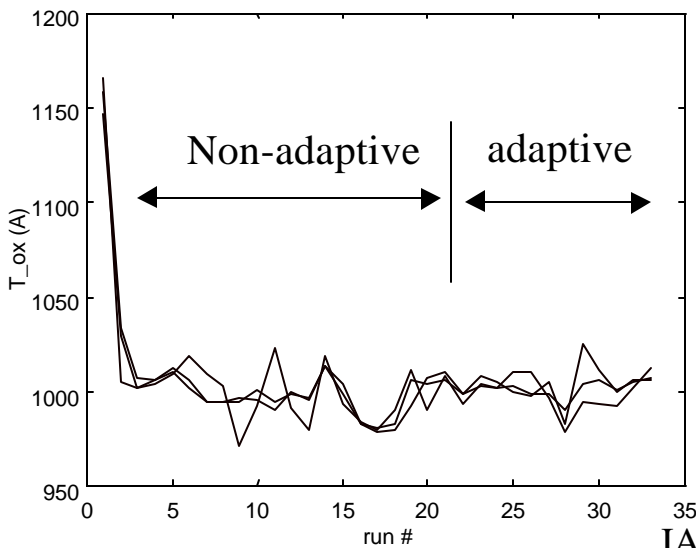


ARRC Implementation

- Wet oxidation test process at AMD
- 22-measurement initial model to establish nominal model parameters and noise variance
- Inputs: Time, Door/Source differential temperature set-points
- Outputs: Center, door, source average thickness
- Diagonal dominance (can use diagonal controller)
- Manual data collection and recipe adjustment (for this test)

ARRC Implementation (results)

- Non-adaptive and adaptive control test
 - Both “center” the process with reasonable steady-state variance (some adjustment of the control gains may be required)
 - Source zone exhibits larger variance (expected)
 - Manual adjustments are error prone! Complete automation in the final ARRC implementation



Conclusions

- Accuracy and uniformity improvement of process results with ARRC
- Integrated, user-friendly tool for modeling, control, model adaptation and any combinations thereof
- Algorithmic and computational reliability
 - Even when supervised, the tool must make correct decisions to be useful
- Complete automation of data transfers and recipe adjustments
- Fully multivariable versions